

文件编号HXA-L33-09(01)发行日期2020年1月06日

承认规格书

种类:功率电感

系列号: <u>HCDH3D16B-100M</u>

客户料号:

· 2	客户 承 认 栏		
承 认 日 期	年	月	日

(贵司承认后请签署一份返回华信安电子,谢谢!)

厦门华信安电子科技有限公司技术质量部

承 认	确 认	作成
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Power Inductor

HCDH3D16B-100M

	ECN HISTORY LIST					
REV	DATE	DESCRIPTION	APPROVED	CHECKED	DRAWN	
1.0	20/1/06	新 發 行	龙梅	梁峰	王亮	
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註						

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ISND P2

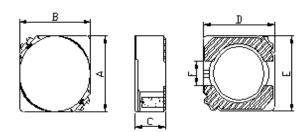
Power Inductor

HCDH3D16B-100M

1. Features

- 1. This specification applies Low Profile Power Inductors.
- 2. 100% Lead(Pb) & Halogen-Free and RoHS compliant.

2. Dimension

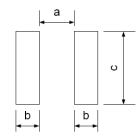


Series	A(mm)	B(mm)	C(mm)	D(mm)	E(mm)	F(mm)
HCDH3D16B	3.8±0.3	3.8±0.3	1.9 MAX	3.6	3.6	1.15





Recommendend Land pattern



a(mm)	b(mm)	c(mm)
1.1TYP	1.65 TYP	4.4 TYP

3. Part Numbering

HCDH 3D16 B - 100 M
A B C D E

A: Series

B: Dimension

C: Control S/N

D: Inductance 100=10 ${\rm uH}$ E: Inductance Tolerance ${\rm M=\pm20\%}$

4. Specification

ISND	Inductance	Tolerance	Test Frequency	DCR	l sat	I rms
Part Number	(uH)	(%)	(Hz)	(Ω) Max	(A)	(A)
HCDH3D16B -100M	10	±20%	0.25V100K	0.190	0.55	0.46

Note:

Isat: Based on inductance change $(\triangle L/L0: \le -35\%)$ @ ambient temp. 25°C`

Irms: Based on temperature rise $(\triangle T: 40^{\circ}C \text{ typ.})$

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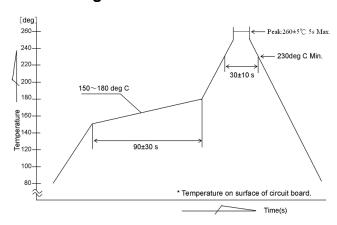
5. Reliability and Test Condition

Item	Performance	Test Method and Remarks		
Operating Temperature	- 40 ~ +125°C.	Including self-generated heat		
Storage Temperature	-40 $^{\sim}$ +85 $^{\circ}\mathrm{C}$ 5 to 40 $^{\circ}\mathrm{C}$ for the product with taping.			
Rated current				
Inductance (L)	Within the specified tolerance	LCR Meter: HP 4285A or equivalent, 100kHz, 0.25V		
DC Resistance		DC Ohmmeter: HIOKI3227 or equivalent		
Temperature characteristics	Inductance change: Within±20%	Measurement of inductance shall be taken at temperature rang within–40°C to +85°C. With reference to inductance value at+20 °C,change rate shall be calculated. Measurement of inductance shall be taken at temperature rang within–40°C to +125°C. With reference to inductance value at+20 °C,change rate shall be calculated.		
Resistance to flexure substrate	No damage.	The test samples shall be soldered to the testing board by the reflow. As illustrated below, apply force in the direction of the arrow indicating until deflection of the test board reaches to 2mm. Process 20 20 20 20 20 20 20 20 20 20 20 20 20		
Adhesion of Terminal electrode	Shall not come off PC board.	The test samples shall be soldered to the testing board and by the reflow. 10 N, 5 s Applied force: 10 N to X and Y directions. Duration: 5s Solder cream thickness: 0.15		
Resistance to Vibration	Inductance change: Within±10% No abnormality observed in appearance.	The test samples shall be soldered to the test board by the reflow. Then it shall be submitted to below test conditions. Frequency: 10-55Hz Total Amplitude: 1.5mm (May not exceed acceleration 196m/S2) Sweeping Method:10Hz to 55Hz to 10Hz for 1min. Time: 2 hours each in X,Y, and Z Direction. Recovery: At least 2hrs of recovery under the standard condition after the test, followed by the measurement within 48hrs.		
Solderability	At least 90% of surface of terminal electrode is covered by new solder.	The test samples shall be dipped in flux, and then immersed in molten solder as shown in below. Flux: methanol solution containing rosin 25% Solder temperature: 245±5°C Time: 5±1.0 sec. Immersion depth: All sides of mounting terminal shall be immersed.		

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Item	Performance		Test Method and Re	emarks
Resistance to soldering		for 40 second seconds,2 time Test board the	ple shall be exposed to ls, with peak temperatu les. ickness: 1.0mm aterial: glass epoxy-res	re at 260±5°C for 5
Thermal shock		reflow. The test samp for specified to sequence.	ples shall be soldered to ples shall be placed at s ime by step 1 to step 4 ure cycles shall be repe	specified temperature as shown below in eated 100 cycles .
Internal Shock		Phase	Temperature(で)	Time(min.)
		1	-40±3℃	30±3
		2	RoomTemp	Within 3
		3	85±2℃	30±3
		4	RoomTemp	Within 3
Damp heat life test	Inductance change: Within±10% No abnormality observed in appearance.	Test Method and Remarks The test samples shall soldered to the test board by the reflow. The test samples shall be placed in thermostatic of specified temperature and humidity as shown in bour Temperature: 60±2°C Humidity: 90-95%RH Time: 500+24/-0 hrs The test samples shall be soldered to the test board.		
Loading under damp heat life test		specified tem current contin Temperature: Humidity: 90-	-95%RH nt: Rated current	and applied the rated
Low temperature life test		The test samples shall be soldered to the test boareflow. After that, the test samples shall be placed at test as shown in below. Temperature:-40±2°C Time:500+24/-0 hrs		
Loading at high temperature life test		reflow. Temperature:	nt: Rated current	o the test board by the

6. Soldering

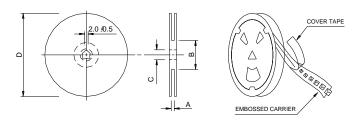


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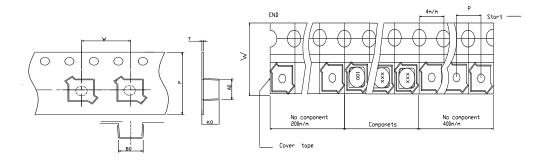
7. Packaging Information

(1) Reel Dimension



Туре	A(mm)	B(mm)	C(mm)	D(mm)
HCDH3D16B	12.4±0.2	100±4.0	13.2±0.2	330±2.0

(2) Tape Dimension



Туре	Ao(mm)	Bo(mm)	Ko(mm)	P(mm)	W(mm)	t(mm)
HCDH3D16B	4.05±0.1	4.05±0.1	2.0±0.1	8.0±0.1	12.0±0.3	0.35±0.05

(3) Packaging Quantity

Туре	Chip / Reel
HCDH3D16B	3500

Application Notice

·Storage Conditions

- To maintain the solderability of terminal electrodes:
- 1. ISND products meet IPC/JEDEC J-STD-020D standard-MSL, level 1.
- Temperature and humidity conditions: Less than 40°C and 60% RH.
 Recommended products should be used within 12 months form the time of delivery.
- 4. The packaging material should be kept where no chlorine or sulfur exists in the air.

·Transportation

- 1. Products should be handled with care to avoid damage or contamination from perspiration and skin oils.
- The use of tweezers or vacuum pick up is strongly recommended for individual components.
 Bulk handling should ensure that abrasion and mechanical shock are minimized.

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单击下面可查看定价,库存,交付和生命周期等信息

>>ISND(华信安)